Computer Architecture (Fall 2022)

Quantitative Approach

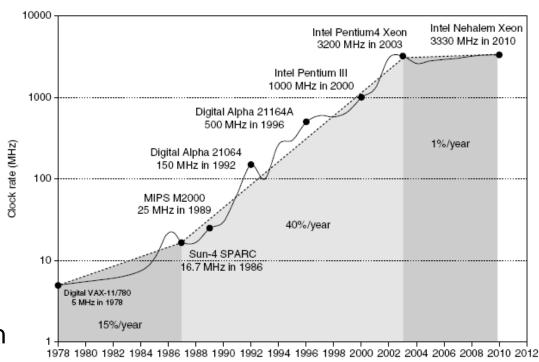
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Power

- Intel 80386 consumed ~ 2
 W
- 3.3 GHz Intel Core i7 consumes 130 W
- Heat must be dissipated from 1.5 x 1.5 cm chip
- This is the limit of what can be cooled by air



Dynamic Power Definition

- Dynamic energy
 - Transistor switch from 0 -> 1 or 1 -> 0

$$Energy_{dynamic} \propto 1/2 \times Capacitive load \times Voltage^2$$

Dynamic power

$$Power_{dynamic} \propto 1/2 \times Capacitive load \times Voltage^2 \times Frequency switched$$

Reducing clock rate reduces power, not energy

Reducing Dynamic Power

- Techniques for reducing power:
 - Do nothing well
 - Dynamic Voltage-Frequency Scaling (DVFS)
 - Low power state for DRAM, disks
 - Overclocking, turning off cores

Dynamic Voltage Frequency Scaling

- Example: H&P5th P23
 - DVFS is a low-power design technique that is becoming pervasive in modern processors
 - Example:

If the voltage and frequency of a processing core are both reduced by 15% what would be the impact on dynamic power?

Power
$$P_{\text{new}} = \frac{C \times (V \times 0.85)^2 \times (F \times 0.85)}{C \times V^2 \times F} = 0.85 = 0.61$$

P_{new} is 61% more power efficient than P_{old}

Static Power Definition

Static power consumption

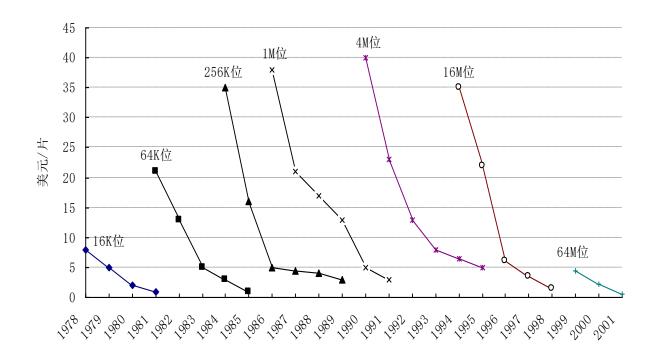
 $Power_{static} \propto Current_{static} \times Voltage$

- Scales with number of transistors
- To reduce: power gating

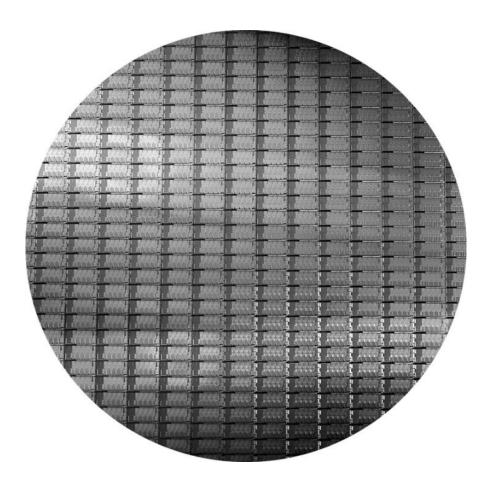
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Cost Trend

- Cost driven down by learning curve
 - Yield
- DRAM: price closely tracks cost
- Microprocessors: price depends on volume
 - 10% less for each doubling of volume



Integrated Circuit Cost



This 300 mm wafer contains 280 full Sandy Bridge dies, each 20.7 by 10.5 mm in a 32 nm process. (Sandy Bridge is Intel's successor to Nehalem used in the Core i7.) At 216 mm2, the formula for dies per wafer estimates 282. (Courtesy Intel.)

Integrated Circuit Cost

Integrated circuit

Cost of integrated circuit =
$$\frac{\text{Cost of die} + \text{Cost of testing die} + \text{Cost of packaging and final test}}{\text{Final test yield}}$$
Cost of die =
$$\frac{\text{Cost of wafer}}{\text{Dies per wafer} \times \text{Die yield}}$$
Dies per wafer =
$$\frac{\pi \times (\text{Wafer diameter/2})^2}{\text{Die area}} - \frac{\pi \times \text{Wafer diameter}}{\sqrt{2 \times \text{Die area}}}$$

Bose-Einstein formula:

Die yield = Wafer yield $\times 1/(1 + \text{Defects per unit area} \times \text{Die area})^N$

- Defects per unit area = 0.016-0.057 defects per square cm(2010)
- N = process-complexity factor = 11.5-15.5 (40 nm, 2010)

Integrated Circuit Cost: Example

Example: H&P 5th P31

Find the number of dies per 300 mm (30 cm) wafer for a die that is 1.5 cm on a side and for a die that is 1.0 cm on a side.

Answer

When die area is 2.25 cm^2 :

Dies per wafer =
$$\frac{\pi \times (30/2)^2}{2.25} - \frac{\pi \times 30}{\sqrt{2 \times 2.25}} = \frac{706.9}{2.25} - \frac{94.2}{2.12} = 270$$

Since the area of the larger die is 2.25 times bigger, there are roughly 2.25 as many smaller dies per wafer:

Dies per wafer =
$$\frac{\pi \times (30/2)^2}{1.00} - \frac{\pi \times 30}{\sqrt{2 \times 1.00}} = \frac{706.9}{1.00} - \frac{94.2}{1.41} = 640$$

Integrated Circuit Cost: Example

Example: H&P 5th P31

Find the die yield for dies that are 1.5 cm on a side and 1.0 cm on a side, assuming a defect density of 0.031 per cm² and N is 13.5.

Answer

The total die areas are 2.25 cm² and 1.00 cm². For the larger die, the yield is

Die yield =
$$1/(1 + 0.031 \times 2.25)^{13.5} = 0.40$$

For the smaller die, the yield is

Die yield =
$$1/(1 + 0.031 \times 1.00)^{13.5} = 0.66$$

That is, less than half of all the large dies are good but two-thirds of the small dies are good.

How to Define Performance?

Airplane	Passenger Capacity	Cruising Range (miles)	Cruising Speed (m.p.h.)	Passenger Throughput (passenger x m.p.h)
Boeing 777	370	4630	610	225,700
Boeing 747	470	4150	610	286,700
Concorde	132	4000	1350	178,200
Douglas DC-8-50	146	8720	544	79,424

Two Key Performance Metrics

- Time to run the task
 - execution time, response time, elapsed time, latency
- Tasks per time unit
 - execution rate, bandwidth, throughput

Airplane	DC to paris	Speed	Passengers	Throughput (passengers x mph)
Boeing 747	6.5 hours	610 mph	470	286,700
Concorde	3 hours	1350 mph	132	178,200

Latency vs. Throughput

- Latency
 - "real" time necessary to complete a task
 - important when the focus is on a single task
 - a computer user who is working with a single application
 - a critical task of a real-time embedded system
 - Throughput (aka Bandwidth)
 - number of tasks completed per unit of time
 - a metric independent from the exact number of executed tasks
 - important when the focus is on running many tasks
 - a manager of a large data-processing center is interested in the total amount of work done in a given time

Example: the Classic 5-Stage Pipeline

Instr. No.	Pipeline Stage							
1	ᄠ	₽	EX	МЕМ	WB			
2		IF	ID	EX	МЕМ	WB		
3			IF	ID	EX	МЕМ	WB	
4				IF	ID	EX	МЕМ	
5					IF	D	EX	
Clock Cycle	1	2	3	4	5	6	7	

Pipelining

- increases the instruction throughput
 - number of instructions completed per unit of time
- but does not reduce (in fact, it usually slightly increases)
 the execution time of an individual instruction

Performance Metrics

Machine X is n times faster than machine Y

$$n = \frac{executionTime(Y)}{executionTime(X)} = \frac{performance(X)}{performance(Y)}$$

- Performance and execution time are reciprocal
 - improve performance → increase performance
 - improve execution time → decrease execution time
- Example
 - executionTime(Y) = 4.8, executionTime(X) = 3.6
 - n = 1.33, i.e. X is 33% faster than Y

Benchmark Suites

- Sets of programs to simulate typical workloads
- Several types
 - real software applications (GCC, Word,...)
 - most accurate but typically longer to process
 - portability problems (OS/compiler dependencies), GUI
 - kernels (Livermore Loops, Linpack,...)
 - small, key pieces taken from real programs
 - limited picture, but good to isolate the performance of individual features of a machine
 - synthetic benchmarks (Whetstone, Dhrystone,...)
 - try to match the average frequency of operations on operands of a real program
 - may easily mislead compiler and hardware designers

Principle of Locality

- Temporal Locality
 - a resource that is referenced at one point in time will be referenced again sometime in the near future
- Spatial Locality
 - the likelihood of referencing a resource is higher if a resource near it was just referenced
- 90/10 Locality Rule of Thumb
 - a program spends 90% of its execution time in only 10% of its code
 - hence, it is possible to predict with reasonable accuracy what instructions and data a program will use in the near future based on its accesses in the recent past
 - this is a consequence of how we program and we store the data in the memory

Principle of Locality - Example

Cache

- directly exploits temporal locality providing faster access to a smaller subset of the main memory which contains copy of data recently used
- but, all data in the cache are not necessarily data that are spatially close in the main memory...
- ...still, when a cache miss occurs a fixed-size block of contiguous memory cells is retrieved from the main memory based on the principle of spatial locality